

Specification For Approval

Date: 2016/12/13

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고객 승인원 관리대장

| | 고객 승인원 관리대장 | | | | | | | |
|------|-------------|---------|-------|------|----|--|--|--|
| 개정번호 | 개정일자 | 개정 Page | 개정이력 | 담당자 | 비고 | | | |
| 00 | 2016.12.13 | 1~10 | 신규 제정 | 장미나 | | | | |
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| | | | | NIV. | | | | |



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Customer: Seoul Semiconductor Co., Ltd

Part Name: A8070-6E

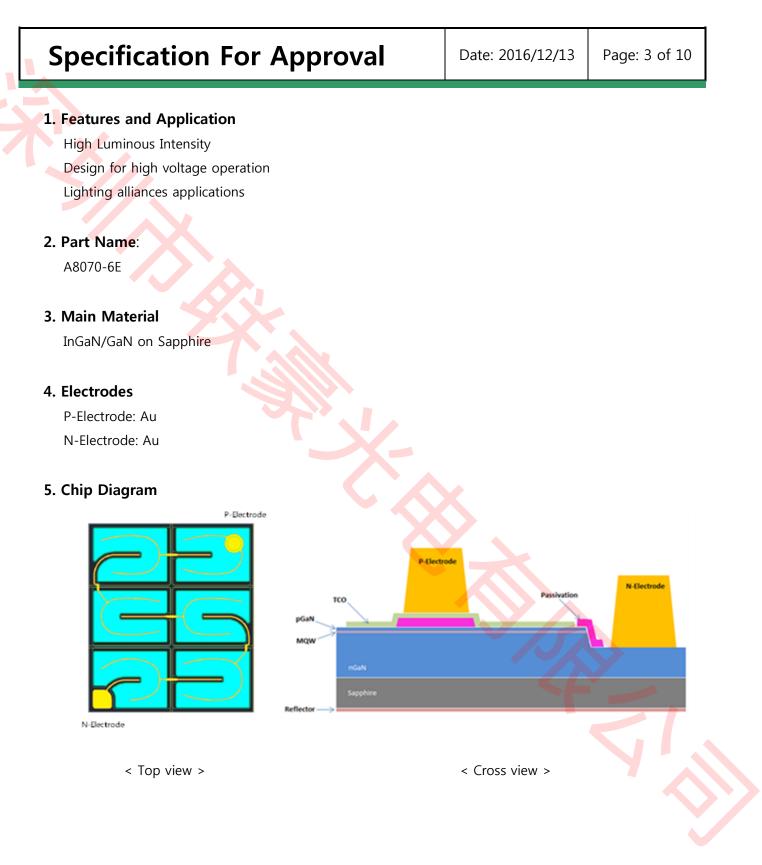
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| Seoul Viosys Co., Ltd. | | | | | |
|---------------------------------|----------|----------|--|--|--|
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| M.N.JANG | K.J.LEE | K.W.KIM | | | |
| 16/12/13 | 16/12/13 | 16/12/13 | | | |

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| Seoul | Seoul Semiconductor Co., Ltd | | | | | |
| Checke | Approved by | | | | | |
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6. Maximum Ratings

| Item | Symbol | Value | Unit |
|---|-----------------|--------------|------|
| DC forward current (Ta=25°C) | I _f | 60 | mA |
| Pulsed forward current ^a (Ta=25°C) | I _{fp} | 70 | mA |
| Junction temperature | Tj | 125 | °C |
| Operating temperature Range | T _{op} | -30 ~ +85 | °C |
| Temperature during packaging | Tp | 250 (<10sec) | °C |

Note. 'Maximum Rating' described means that the chip has the possibility of breaking down when these conditions are exceeded momentarily. 'Maximum Rating' does not guarantee to use it continuously considering life under these conditions. 'Maximum Ratings' concerning your LED device after the chip is built into your package shall be established by yourself since these greatly depend on the design of the device, the conditions of assembly, the environment used, and so forth.

7. Typical Electro-Optical Characteristics at Ta=25°C

| Parameter | Symbol | Condition | Min. | Тур. | Max. | Unit |
|-----------------------------------|----------------------|------------------------|------|------|------|------|
| Turn-on voltage | V_{F1} | I _F =100 μA | 13.8 | - | 16.2 | V |
| Forward voltage ^{a)} | V_{F2} | $I_F = 50 \text{mA}$ | 17.8 | - | 19.6 | V |
| Dominant wavelength ^{b)} | λ_{D} | I _F =50mA | 450 | | 460 | nm |
| Radiant power ^{c)} | Ро | I _F =50mA | 460 | | 700 | mW |

Radiant and Peak wavelength and voltage are measured by Seoul Viosys's equipment.

• Electrostatic Discharge (ESD) protection epitaxy layer is applied.

Electrostatic Discharge (ESD) protection is strongly recommended when handling chips

I_F: Forward Current

^aTolerance of measured Forward Voltage : $\pm 3\%$

^bTolerance of measured Dominant Wavelength : ±1nm

^cTolerance of measured Radiant Power : ±10%

8. Mechanical Specifications

| Description | Dimension (um) | Tolerance |
|----------------|----------------|-----------|
| Chip size | 800x700 | ±10% |
| Chip thickness | 180 | ±10um |
| p-pad diameter | 80 | ±10um |
| n-pad diameter | 80 | ±10um |



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9. Visual inspection

| Item | NG criteria | NG Example |
|------------------------------|--|------------|
| Pinhole | Larger than 5% of surface emitting area | |
| Surface contamination | Surface contamination Larger than 10% of surface emitting area | |
| Pad contamination | Pad contamination Larger than quarter of pad bonding area | |
| Surface scratches | Larger than 10% of surface emitting area | |
| Pad scratch | Larger than 50% of pad area (Including probing mark) | |
| TCL film peeling | Larger than 10% of surface emitting area | |
| Partially missing P/N Pad | Larger than 10% of bond pad area Larger than 2/3 of finger pad area | |
| Back metal Peeling | Larger than 10% of chip area | |



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|---|-------------------|---|-----------------|--------|---------------|
| ł | Pad metal Residue | Larger than 10% of chip surface a | rea | | |
| | Dicing shift | The light-emitting surface, N-pad and P-pad c | an't be cut-off | | |
| | Chipping | N-Pad, P-Pad or TC line chipped | off | | |
| | Bad cut | Extrusion ✓ Out of chip size tolerance ✓ Including the pad metal of other | chips | | |
| | Twins or triplets | Inseparable chips | | | |
| | θ shift | θ > ±5° (10°) | | | e e |

10. Sorting Bins and Product Name (Rev.4)

| 10. Sorting Bins and P | roduct Name (Rev.4) | | |
|------------------------|---------------------|--------------------|---------|
| (1) Sorting Bins | | | |
| V _{F1} (V) | V _{F2} (V) | λ_{D} (nm) | Po (mW) |
| 13.8~16.2 | 17.8~18.4 | 450~452.5 | 470~480 |
| | 18.4~19 | | 480~500 |
| | 19~19.6 | | 500~520 |
| | | - | 520~540 |
| | | | 540~700 |



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| V _{F1} (V) | V _{F2} (V) | λ_{D} (nm) | Po (mW) |
|---------------------|---------------------|--------------------|---------|
| 13.8~16.2 | 17.8~18.4 | 452.5~455 | 460~480 |
| | 18.4~19 | 455~457.5 | 480~500 |
| | 19~19.6 | 457.5~460 | 500~520 |
| | | | 520~540 |
| | | | 540~700 |

(2) Product Name: A8070-6E-*1*2*3*4

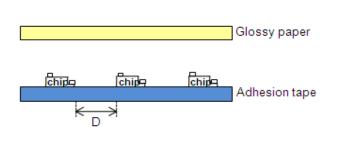
| * * * | | *1* | 2*3 | |
|---------|-------------|-------------|-------------|-------------|
| *1*2*3 | 450~452.5nm | 452.5~455nm | 455~457.5nm | 457.5~460nm |
| 460~480 | | Z46 | A46 | B46 |
| 470~480 | Y47 | - | - | - |
| 480~500 | Y48 | Z48 | A48 | B48 |
| 500~520 | Y50 | Z50 | A50 | B50 |
| 520~540 | Y52 | Z52 | A52 | B52 |
| 540~700 | Y54 | Z54 | A54 | B54 |

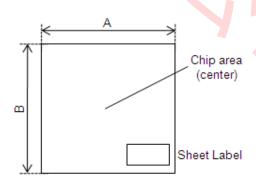
| *4 | 17.8~18.4 | 18.4~19 | 19~19.6 |
|-------|-----------|---------|---------|
| Grade | L | М | Н |

11. Packing

- (1) Chips on tape
 - (a) Electro-Optical measurement data should be labeled and tacked on the backside of the glossy paper. Chip area should be placed in the center of adhesion tape, and the wire-bonding pad should face towards the covered glossy paper.

(b)







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(b) Chip type, Lot No. and quantity etc. should be labeled and tacked to the corner of the glossy paper.

| Item | Instruction |
|---------------------|------------------------|
| Adhesion tape | Semi- transparent blue |
| Glossy paper (A×B) | 197mm × 220mm |
| Chip Qty tape | Тур. 6,200еа |
| Chip separation (D) | D : 0.2mm |

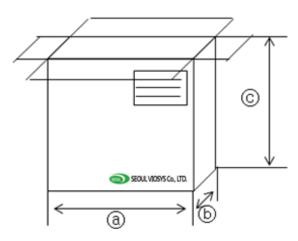
- (2) Packing for shipment
 - (a) The sheets (adhesion tape + glossy paper) are packed in an anti-static electricity bag. Each antistatic bag can contain up to 20 sheets.
 - (b) The anti-static bags are packed in a box. The size of this box is 250mm×65mm×275mm

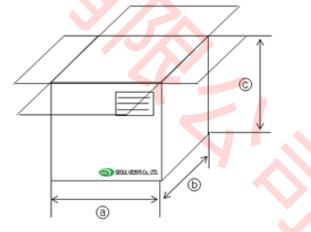
(a) \times (b) \times (c)). Each box can contain up to 5 anti-static electricity bags.

(c) The boxes which contain anti-static electricity bags are packed in the other box.

The size of this outer box is $260 \text{ mm} \times 340 \text{ mm} \times 290 \text{ mm}$ (a) × (b) × (c)). Each outer box can contain up to 5 inner boxes.

(d) Each sheet / box is labeled with information describing its content. (Details please refer to section 11)







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12. Labeling

| Sheet | Inner Box | Outer Box |
|------------------------|--|--|
| SEOUL VIOSYS Co., LTD. | LOT ID : XXXXXXXXX MODEL : XXXXXXXXX SHEET QTY : CHIP QTY : | LOT ID : XXXXXXXXX MODEL : XXXXXXXXX SHEET QTY : CHIP QTY : |

(1) Sheet: The measurement data for each lot are also shown on the backside of the sheet.

(2) Inner Box: The information about the products is also shown on the inner box.

(3) Outer Box: The information about the products is also shown on the outer box

13. Precaution

(1) Quality Guarantee

The chip guarantee period is three months after the delivery under the following preservation conditions. If any defective is found, the customer shall immediately inform of that to Seoul Viosys Co., Ltd. Preservation conditions (when the shipping package is unopened.)

- \cdot Temperature: 0 ~ 60 °C
- · Atmosphere: Keep the chips in a desiccator with silica gel or with nitrogen substitution.
- (2) General precaution for use
- Chips should be stored in a clean environment. If the Chips are to be stored for 3 months or more after being shipped from Seoul Viosys, they should be packed by a sealed container with nitrogen gas injected. (Shelf life of sealed bags: 1year, 0~40°C of temperature, 20~70% of RH)
- This chip should not be used directly in any type of fluid such as water, oil, organic solvent, etc. When washing is required, IPA is recommended to use.
- After storage bag is open, device subjected to soldering, solder flow, or other high temperature processes must be: Mounted within 168 hours (7days) at an assembly line with a condition of no more than 30°C and 60% RH
- Chips require baking before mounting, if humidity card reading is >60% at, 23.5°C. Chips must be baked for 24Hrs. at 65.5°C, if baking required.
- \cdot When the chips are illuminating, the maximum ambient temperature should be first considered



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- before operation. If voltage exceeding the absolute maximum rating is applied to chips, it may cause damage or even destruction to chips. Damaged LEDs will show some abnormal characteristics such as remarkable increase of leak current, lower turn-on voltage and getting unlit at low current.
- The appearance and specifications of the products may be modified for improvement without further notice.
- The chips are sensitive to the static electricity and surge. It is strongly recommended to use a grounded wrist band and anti-electrostatic glove when handling the LEDs.

The above specifications are subject to change with prior notice.

Seoul Viosys Co., Ltd DEC 13th 2016